

Scope of the workshop

X-ray fluorescence (XRF) spectrometry is among the rapidly evolving non-destructive techniques, with the potential to provide two- or three-dimensional quantitative information on the elemental distributions within the probed sample volume with trace-level detection limits down to the (sub)micrometer scale. The fast development of laboratory and synchrotron sources, coupled with advanced X-ray focussing optics and fast ED-detectors opened new possibilities in X-ray fluorescence methods in terms of achievable spatial resolution, sensitivity and scanning strategies.

The accurate quantitation of XRF data-sets, however, remains to date a challenge. The workshop responds to this challenge, with the aim to provide the researchers practical knowledge on the different approaches of XRF quantitation, and an opportunity for information exchange between novice and experienced researchers working in the field of XRF (micro)spectrometry.

The programme of the two-day workshop will consist of invited and a limited number of contributed lectures, followed by discussions on practical problems of quantitative XRF-spectrometry introduced by the keynote speakers.

Workshop Secretariat

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European Workshop on Quantitative Analysis in X-ray Fluorescence Spectrometry

October 13-14, 2005
Ghent University, Ghent, Belgium



Organized by the Department of Analytical Chemistry, Ghent University in collaboration with the European X-ray Spectrometry Association (EXSA) and the financial support of the Research Foundation - Flanders (FWO).

Scientific Topics:

- Interaction of X-rays with matter, comparison of X-ray cross-section/fundamental parameter data bases for XRF-spectrometry
- Fundamental parameter quantification methods
- Monte Carlo models for XRF-spectrometry, Reverse Monte Carlo based XRF quantification algorithms
- Data reduction techniques for 2D/3D micro-XRF data sets, quantitative XRF-microtomography and confocal XRF imaging
- Applications of quantitative XRF (micro)spectrometry

EXSA General Assembly

The meeting will host the annual general assembly of EXSA, which will take place on October 13, 2005.

Scientific Advisory Committee:

Burkhard Beckhoff, Berlin, Germany
Gerald Falkenberg, Hamburg, Germany
Alexandre Simionovici, Grenoble, France
Imre Szalóki, Debrecen, Hungary
Bruno Vrebos, Almelo, The Netherlands
Luc Moens, Ghent, Belgium
Pierre Van Espen, Antwerp, Belgium
René Van Grieken, Antwerp, Belgium
Maria Luisa de Carvalho, Lissabon, Portugal

Invited speakers

George Havrilla (keynote speaker, USA)
Michael Mantler (keynote speaker, Austria)
Wolfgang Malzer (Germany)
Janos Osan (Hungary)
Christian Schroer (Germany)
Rolf Simon (Germany)
Bart Vekemans (Belgium)



Venue

The workshop will be held in the old Dominican monastery "Het Pand" of Ghent University, located in the heart of the city on the banks of the river Leie, near the medieval port with the guildhalls as its remnants.

Organizing Committee:

Laszlo Vincze (chairman), UGent
Annemie Adriaens, UGent
Karel Strijckmans, Ugent
Carlo Vandecasteele, KU Leuven
Koen Janssens, University of Antwerp
Karolien De Wael, UGent
Jan De Gruyter, UGent
Karen Leyssens, UGent
Karl Peeters, UGent
Bart Schotte, UGent
Ine Vanmoortel, UGent

Abstracts

Abstracts of contributions to be presented during the workshop should be sent in electronic format (Word or PDF document) as an e-mail attachment to the Workshop Secretariat by 1st of September, 2005.

Important deadlines

Submission of abstracts: September 1, 2005 (extended from August 1)

Early registration deadline: September 1, 2005

Registration fee

- Regular participants: € 50.00 (before September 1)
€ 100.00 (after September 1)
- Students: € 50.00